

JOURNAL OF ELECTRONIC TESTING:
Theory and Applications
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Editorial

V.D. Agrawal 1

New Editors – 2022 3

2021 Reviewers 5

Test Technology Newsletter 7

HARDWARE SECURITY

Hardware Obfuscation for IP Protection of DSP Applications
Naveenkumar R · N.M. Sivamangai · Napolean A · G.A. Nissi 9

ANALOG AND RF CIRCUIT TESTING

Revisit to Histogram Method for ADC Linearity Test: Examination
of Input Signal and Ratio of Input and Sampling Frequencies
Y. Zhao · K. Katoh · A. Kuwana · S. Katayama · J. Wei · H. Kobayashi ·
T. Nakatani · K. Hatayama · K. Sato · T. Ishida · T. Okamoto ·
T. Ichikawa 21

REVERSIBLE CIRCUITS

Synthesis of Reversible Circuits with Reduced Nearest-Neighbor
Cost Using Kronecker Functional Decision Diagrams
D. Bu · J. Yan · P. Tang · H. Yuan 39

RADIATION HARDENING AND INTERFERENCE

A Low Power-Consumption Triple-Node-Upset-Tolerant
Latch Design
Y. Lu · G. Hu · J. Wang · H. Wang · L. Yao · H. Liang ·
M. Yi · Z. Huang 63

A New Neural Network Based on CNN for EMIS Identification
Y.-c. Xiao · F. Zhu · S.-x. Zhuang · Y. Yang 77

AGING AND RELIABILITY

Design of Power Gated SRAM Cell for Reducing the NBTI Effect
and Leakage Power Dissipation During the Hold Operation
A. Bhattacharjee · A. Nag · K. Das · S.N. Pradhan 91

BUILT-IN SELF-TEST

A Low-cost BIST Design Supporting Offline and Online Tests
A. Menbari · H. Jahanirad 107

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